



**Crystallographic Defects and Mechanical Strength of Micron Size Monocrystalline Diamond**

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# **Outline**

- 
- v **Introduction**
- v **Experimental Techniques**
- v **Experimental Results**
- v **Summary**
- v **Conclusions**



## **Crystallographic Defects of Diamond**



- **Crystallographic defects or crystal growth defects of** diamond are the result of the nucleation and crystal growth processes that govern the catalytic high pressure-high temperature (HPHT) graphite to diamond transformation (so called diamond synthesis process)
- v Crystallographic defects (substitutional or interstitial impurities, vacancies, dislocations, etc.), are sources of mechanical stresses, thus contributing to mechanical strength and fracture characteristics of monocrystalline diamond particles



# **Crystallographic Defects of Diamond**



- $\clubsuit$  The intrinsic properties of diamond crystals are determined by the particularities of the catalytic HP-HT synthesis process; mainly the nucleation & growth rates
- ❖ For a given graphite-metal catalyst system the kinetics of the diamond synthesis process (nucleation & growth rates) is controlled via thermodynamic parameters pressure & temperature
	- E Low nucleation & growth rates  $\rightarrow$  diamond crystals with low level of crystal growth (CG) defects  $\rightarrow$  high mechanical strength
	- High nucleation & growth rates  $\rightarrow$  diamond crystals with high level of crystal growth (CG) defects  $\rightarrow$  low mechanical strength



# **Micron Size Monocrystalline Diamond**



- ❖ Most micron size monocrystalline diamond powders are produced by size reduction (milling) of mesh size diamond powders (starting mesh diamond powder feed)
- **\*** Following the micronizing process (mechanical, chemical, and thermal process steps):
	- § A large number of the *initial crystal growth (CG) defects* of the starting mesh diamond powder feed *are released*
	- Some of the initial crystal growth (CG) defects of the starting mesh *diamond powder feed are transmitted to the resultant micron size diamond powder as residual crystal growth (RCG) defects*



# **Mechanical Strength of Diamond**

6

- $\cdot$  Mechanical strength of diamond particle characterizes its ability to resist fracture under static or dynamic (impact) loading
- **\*** Mechanical strength of monocrystalline diamond particle is dependent upon particle size, particle shape and concentration of residual crystal growth (RCG) defects





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- $\mathbf{\hat{P}}$  For a given size and shape, the mechanical strength of a micron size monocrystalline diamond particle is directly related to the concentration of residual crystal growth (RCG) defects:
	- Low concentration of RCG defects  $\longrightarrow$  High mechanical strength
	- High concentration of RCG defects **Low** mechanical strength





### **DR-FTIR Spectroscopy**

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- $\cdot$  The concentration of crystallographic defects of micron size monocrystalline diamond powders was gauged using the Diffuse Reflectance Fourier Transform Infrared (DR-FTIR) Spectroscopy



Fig. 1 – Schematic view of FTIR transmission spectroscopy with a diffuse reflectance accessory 8



#### **DR-FTIR Spectroscopy**



- ❖ Diffuse reflectance FTIR is a technique well suited for analysis of powder samples that can give quantitative and qualitative information about the nature and level of impurities and crystalline defects
- $\dots$  FTIR transmittance is related to elastic light scattering due to crystallographic defects such as dislocations and grain boundaries



# **DR-FTIR Spectrum of Diamond**

- ❖ 2670 to 1600 cm-1 represents transmittance from the C=C bonding
- ❖ 1400 to 1050 cm-1 contains peaks due to Nitrogen defects:
	- § A centers, B centers, C centers (single substitutional N at 1130 & 1344 cm-1) and platelets



Fig. 2 – DR-FTIR spectrum of diamond



 $\clubsuit$  Different  $\mu$  size diamond powder types sharing "identical" size

- $6-12 \mu m$  HQ-MB = High quality metal bond diamond
- $6-12 \mu m$  LQ-MB = Low quality metal bond diamond



 $6-12 \mu m$  RB = Resin bond diamond



- ❖ FTIR baseline transmittance
	- FTIR baseline transmittance mirrors the concentration of crystallographic defects (residual crystal growth defects) of micron size monocrystalline diamond powders – **the higher the concentration of crystallographic defects, the lower the baseline transmittance**



Fig. 5 – Overlay of FTIR baseline transmittance of 6-12 µm diamond samples



# **Crystallographic Defects & FTIR Baseline**

- $\cdot$  RB diamond sample which possesses intrinsically high concentration of crystallographic defects, exhibits a much lower FTIR baseline transmittance compared to MB diamond samples
- ◆ MB diamond samples possess much lower concentration of crystallographic defects and, consequently, exhibit much higher FTIR baseline transmittance
- v *FTIR baseline transmittance represents a good measure for the concentration of crystallographic defects in micron size monocrystalline diamond powders*



- $\clubsuit$  Different quality  $\mu$  size metal bond (MB) diamond powder sharing "identical" particle size & shape
	- 12-22  $\mu$ m HQ-MB = high quality metal bond diamond
	- $12-22 \mu m$  LQ-MB = low quality metal bond diamond





Fig. 6 – PSD overlay

Table 1 – Particle shape & size data



 $\mathbf{\hat{P}}$  FTIR spectroscopy results on different quality  $\mu$  size metal bond (MB) diamond powder sharing "identical" particle size & shape



Fig.  $7$  – Overlay of FTIR spectra of 12-22  $\mu$ m diamond samples



# **Substitutional Nitrogen Impurities in Synthetic Diamond**

 $\triangle$  Substitutional Nitrogen impurities in synthetic diamond (Type Ib)

- $\cdot$  It is known that the amount and defect type of substitutional nitrogen in synthetic diamond strongly influences crystal strength
- $\clubsuit$  Generally, the concentration of the substitutional Nitrogen impurities in the type Ib diamond is proportional to the intensity of the band at 1130 cm−1
- $\lozenge$  The substitutional N defect (SND) concentration is calculated as the ratio of the percent transmission of the diamond peak (at 2160cm-1) and the single N defect peak (at 1130cm-1) as follows:

**SND = (% transmission @ 2160 cm-1) / (% transmission @ 1130 cm-1)**



 $\dots$  FTIR baseline transmittance and substitutional Nitrogen defect









- $\clubsuit$  Both 12-22 µm HQ-MB and LQ-MB diamond samples show similar concentration of the substitutional Nitrogen defect
- $\triangle$  There is a noticeable difference between the baseline transmittance of the two diamond samples, with HQ-MB diamond exhibiting a higher baseline transmittance and therefore, lower concentration of crystallographic defects



### **Raman Spectroscopy**

- $\dots$  Macro Raman spectroscopy to complement FTIR spectroscopy
	- $\cdot$  The change in the Raman intensity may be caused by increase in the elastic (Rayleigh) scattering of light from crystallographic defects
	- **\*** More defects such as lattice dislocations would tend to elastically scatter more of the incident beam and reduce the inelastically scattered Stokes or anti-Stokes Raman scattering



Fig. 9 – Schematic view of Raman spectroscopy



### **Raman Spectroscopy – Results**

Raman spectroscopy results on different quality  $\mu$  size metal bond (MB) diamond powder sharing "identical" particle size & shape









# **FTIR & Raman Spectroscopy – Results**

❖ Correlation between FTIR baseline transmittance & Raman diamond peak



Fig.  $11$  – FTIR & Raman Spectroscopy results of 12-22  $\mu$ m diamond samples

v *The macro Raman spectroscopy results on same diamond powders (12-22* µ*m HQ-MB and 12-22* µ*m LQ-MB) show that the change in intensity of the diamond peak at 1332 cm-1, correlates well with FTIR base line transmittance* 21

#### **Crushing Strength Testing of** µ **Size Diamond** INTERTECH **2013**





Fig. 12 – Crushing strength apparatus (US Patent 7,275,446)



Fig. 13 – Schematic representation of the crushing strength testing

**Crushing Strength Testing of** µ **Size Diamond**INTERTECH Z013

❖ Crushing Strength Index (CSI)

#### **CSI = ROS/IOS x 100**

**IOS**: initial number of on-size particles (50-95% of number distribution before crushing) **ROS**: resulting number of on-size particles (50-95% of number distribution after crushing)



Fig. 14 – PSD overlay of uncrushed and crushed diamond powder (example)  $23$ 



 $\cdot$  CSI of different quality  $\mu$  size metal bond (MB) diamond powder sharing "identical" particle size & shape



Fig. 15 – Crushing Strength Index (CSI) of  $12-22 \mu m$  diamond samples



v FTIR baseline transmittance & CSI of different quality µ size metal bond (MB) diamond powder sharing "identical" particle size &





Fig. 16 – Correlation between FTIR baseline transmittance and crushing strength index (CSI) of 12-22 µm diamond samples



- **<sup>❖</sup>** Experimental results established that the *FTIR baseline transmittance represents a good measure of the concentration of crystallographic defects*, *which* (for a given particle shape and particle size distribution) *is directly related to the mechanical strength of micron size monocrystalline diamond powders*
	- § HQ-MB micron diamond powder exhibits higher FTIR baseline transmittance (BT), which indicates lower concentration of crystallographic defects. Mechanical strength expressed as crushing strength index (CSI) is higher
	- LQ-MB micron diamond powder exhibits lower FTIR baseline transmittance (BT), which indicates higher concentration of crystallographic defects. Mechanical strength expressed as crushing strength index (CSI) is lower





#### $\clubsuit$  Different  $\mu$  size diamond powder types sharing similar (?) size

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Fig. 17 – PSD overlay of 30-40  $\mu$ m diamond samples



 $\clubsuit$  FTIR spectroscopy results on different  $\mu$  size diamond powder types





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#### **Experimental Results**

v Different µ size diamond powder types sharing "similar" particle size & shape30-40 HQ2-MB.#M3







Fig. 19 – PSD overlay of 30-40 mm diamond samples

v FTIR spectroscopy results on different µ size diamond powder types sharing "similar" particle size & shape

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**Experimental Results**



Fig. 20 – Overlay of FTIR spectra of 30-40  $\mu$ m diamond samples

30



 $\cdot$  CSI of different  $\mu$  size diamond powder types sharing "similar" particle size & shape



Fig. 20 – Crushing Strength Index (CSI) of 30-40  $\mu$ m diamond samples



#### **Summary**

 $\diamond$ *The objective of this work was to investigate the correlation, between the concentration of crystallographic defects of micron size monocrystalline diamond powders and their mechanical strength*

Experimental results showed that *the FTIR baseline transmittance of micron size monocrystalline diamond powders represents a good measure of the concentration of crystallographic defects* (residual crystal growth defects) *which* (for a given particle shape and size distribution) *is directly related to their mechanical strength*, expressed as crushing strength index (CSI)



## **Conclusions**

- $\dots$ *High quality metal bond micron diamond powder* (produced from high quality mesh diamond powder feed), *exhibits increased FTIR baseline transmittance*, which indicates *low concentration of crystallographic defects* and, consequently, *high mechanical strength*
- v *Low quality metal bond micron diamond powder*  (produced from low quality mesh diamond powder feed), exhibits *lower FTIR baseline transmittance* which indicates *higher concentration of crystallographic defects* and, therefore *lower mechanical strength*
- **<sup>❖</sup> Resin bond micron diamond powder** (produced from resin bond mesh diamond powder feed), exhibits *lowest FTIR baseline transmittance*, which indicates *highest concentration of crystallographic defects* and, accordingly, *lowest mechanical strength*  $33$



# **Thank you!**

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